

Issue Classification				Application/Control No.	Applicant(s)/Patent under Reexamination	
				10/003,831	NAKANO ET AL.	
				Examiner	Art Unit	
				Aaron W. Carter	2625	

ISSUE CLASSIFICATION								
ORIGINAL		CROSS REFERENCE(S)						
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)					
382	145	382	149	151				
INTERNATIONAL CLASSIFICATION		438	16					
G	0	6	K	9/00	348	87		
H	0	1	L	23/544	257	E23.17	9	
				/	356	237.1		
<p style="text-align: right;">AUC</p> <p>Aaron Carter 9/8/2005 (Assistant Examiner) (Date)</p> <p><i>Shane H. Lee 9-13-05</i> (Legal Instruments Examiner) (Date)</p>				 <p>BHAVESH M. MEHTA SUPERVISORY PATENT EXAMINER <small>Primary Examiner</small> TECHNOLOGY CENTER 2600 <small>(Date)</small></p>			<p>Total Claims Allowed: 4</p> <p>13</p>	
							O.G. Print Claim(s)	O.G. Print Fig.
							13	1A

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
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7		37		67	97	127	157
8		38		68	98	128	158
9		39		69	99	129	159
10		40		70	100	130	160
11		41		71	101	131	161
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